

## Method and appliance for detecting, identifying and relocating defects in a material strip

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### Abstract

The invention relates to a device and a method for detecting, identifying and relocating defects in a material strip of great length. In order to enable defects to be relocated reliably and quickly with relatively little effort, the material strip is checked for defects, and position indicators are applied to the material strip continuously over its length. In the event of a defect being observed, an associated defect position indicator is stored, and during the subsequent relocation of a defect, a current starting position indicator is established, and the material strip is moved over a conveying length which is calculated from the established starting position indicator and the stored defect position indicator.

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